Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/040,915	TEIG ET AL.	
Examiner	Art Unit	
A. M. Thompson	2825	

SEARCHED			
Class	Subclass	Date	Examiner
716	12	1/1/2006	АМТ
716	13	1/1/2006	AMT
716	14	1/1/2006	AMT
716	15	1/1/2006	AMT

	INTERFERENCE SEARCHED			
niner	Examin	Date	Subclass	Class
ит	АМТ	1/1/2006	12	716

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPAT; USPGPUB; DERWENT	1/1/2006	AMT	